LTC2916CTS8-1#TRMPBF | Data Sheet

## Qualification Summary:

| STRESS TEST | TEST CONDITIONS *1 | REFERENCE TEST METHOD | NUMBER OF LOTS | SAMPLE SIZE PER LOT | RESULTS |
|---|---|---|---|---|---|
| High-Temperature Operating Life (HTOL) | $T_J \geq 125°C$, 1000 hrs | JESD22-A108 | 3 | 77 | Pass |
| High-Temperature Storage Life (HTSL) | $T_A \geq 150°C$, 1000 hrs | JESD22-A103 | 3 | 25 | Pass |
| MSL Preconditioning | Per MSL | J-STD-020<br>JESD22-A113 | — | — | Classification |
| Temperature Cycling (TC) | -65°C to +150°C, 500 cycles | JESD22-A104 | 3 | 25 | Pass |
| Temperature Humidity Bias (THB) or Biased HAST (HAST) | 85°C/85%RH, 1000 hrs or<br>130°C/85%RH, 96 hrs, respectively | JESD22-A101 or<br>JESD22- A110, respectively | 3 | 25 | Pass |
| Autoclave (AC) or<br>Unbiased HAST (UHAST) | 121°C/100%RH, 96 hrs or<br>130°C/85%RH, 96 hrs, respectively | JESD22-A102,<br>JESD22-A118, respectively | 3 | 25 | Pass |
| ESD Human Body Model (HBM) | $T_A = 25°C$ | JS-001 | 1 | 3 | See Data Sheet/ Contact Us |
| ESD Charge Device Model (CDM) | $T_A = 25°C$ | JS-002 | 1 | 3 | See Data Sheet/ Contact Us |
| Latch-Up | Per JESD78 | JESD78 | 1 | 3 | Pass |

1. *Or equivalent JEDEC conditions*

For FIT/ MTTF estimates, visit FIT/ MTTF

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